

**A new measure for calculating multiple fault coverage of microprocessor self-test**

**Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes** BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill [http://www.ester.ee/record=b2150914\\*est](http://www.ester.ee/record=b2150914*est)

**Mixed-level identification of fault redundancy in microprocessors**

**Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Gürsoy, Cemil Cem; Raik, Jaan** LATS 2019 : 20th IEEE Latin American Test Symposium : Santiago, Chile, March 11th - 13th 2019 2019 / 6 p. : ill <https://doi.org/10.1109/LATW.2019.8704591>